

TEST REPORT

OF

FCC CFR 47 part 1, 1.1307(b), 1.1310

FCC ID: A3LEPPA510

Equipment Under Test : WIRELESS CHARGER
Model Name : EP-PA510
Applicant : Samsung Electronics Co., Ltd.
Manufacturer : Samsung Electronics Co., Ltd.
Date of Test(s) : 2015.08.28 ~ 2015.09.10
Date of Issue : 2015.09.14

In the configuration tested, the EUT complied with the standards specified above.

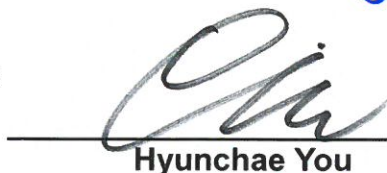
Tested By:


Jaeha Chung

Date:

2015.09.14

Approved By:


Hyunchae You

Date:

2015.09.14

The results shown in this test report refer only to the sample(s) tested unless otherwise stated. This test report cannot be reproduced, except in full, without prior written permission of the Company.

INDEX

<u>TABLE OF CONTENTS</u>	Page
1. General Information -----	3
2. Test Result -----	5

The results shown in this test report refer only to the sample(s) tested unless otherwise stated. This test report cannot be reproduced, except in full, without prior written permission of the Company.

1. General information

1.1. Testing laboratory

SGS Korea Co., Ltd. (Gunpo Laboratory)

- Wireless Div. 2FL, 10-2, LS-ro 182beon-gil, Gunpo-si, Gyeonggi-do, Korea, 435-837

All SGS services are rendered in accordance with the applicable SGS conditions of service available on request and accessible at <http://www.sgs.com/en/Terms-and-Conditions.aspx>.

Phone No. : +82 31 688 0901

Fax No. : +82 31 688 0921

1.2. Details of applicant

Applicant : Samsung Electronics Co., Ltd.

Address : 129, Samsung-ro, Yeongtong-gu, Suwon-si, Gyeonggi-do, 16677 Republic of Korea

Contact Person : Kim, Kyung-Won

Phone No. : +82 31 301 0274

1.3. Description of EUT

Kind of Product	WIRELESS CHARGER
Model Name	EP-PA510
Power Supply	DC 5.0 V
Frequency Range	120 kHz ~ 190 kHz
Operating Conditions	-20 °C ~ 60 °C
Antenna Type	Inductive loop coil antenna
H/W Version	REV0.1
S/W Version	0913

The results shown in this test report refer only to the sample(s) tested unless otherwise stated. This test report cannot be reproduced, except in full, without prior written permission of the Company.

1.4. Test Equipment List

Equipment	Manufacturer	Model	S/N	Cal Date	Cal Interval	Cal Due.
E-Field Probe	ETS-LINDGREN	HI-6005	00047870	Mar. 11, 2015	Annual	Mar. 11, 2016
Magnetic Field Sensor	HIOKI	0850-B1	3471	Jul. 16, 2015	Annual	Jul. 16, 2016
Magnetic Field Hitester	HIOKI	FT3470-50	140430999	Jul. 16, 2015	Annual	Jul. 16, 2016
Anechoic Chamber	SY Corporation	L × W × H (9.6 m × 6.4 m × 6.6 m)	N/A	N.C.R.	N/A	N.C.R.

1.5. Test report revision

Revision	Report number	Date of Issue	Description
0	F690501/RF-RTL009128	2015.09.14	Initial

1.6. Worst case of test configurations

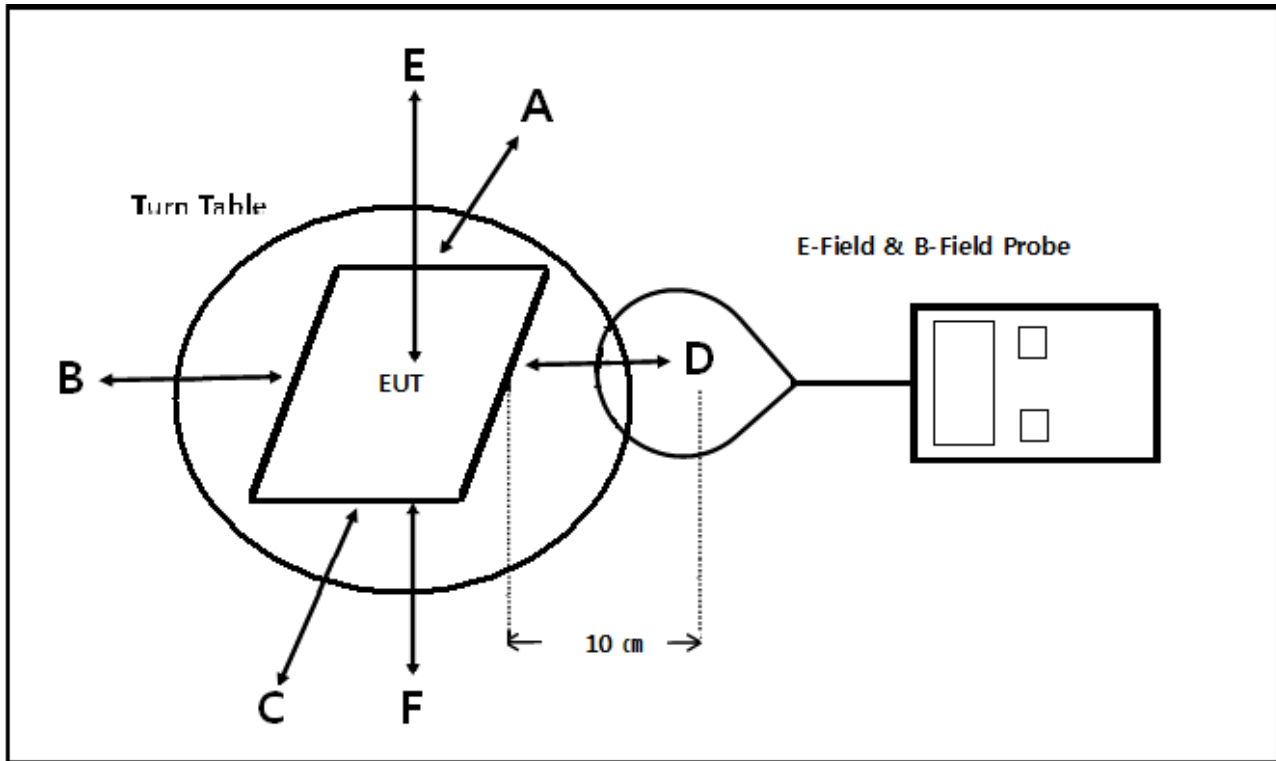
In order to check all kinds of possible configurations, EUT was evaluated with appropriate client and under each charging condition as below table.

EUT configuration	Description
Charging Mode with client device (Galaxy S 6 : SM-G920A FCC ID : A3LSMG920A)	Less than 1 % of battery
	Less than 50 % of battery
	100 % full charging of battery

The results shown in this test report refer only to the sample(s) tested unless otherwise stated. This test report cannot be reproduced, except in full, without prior written permission of the Company.

2. Test Result

2.1. Test Setup



2.2. Measurement procedure

- The RF exposure test was performed in anechoic chamber.
- The measurement probe was placed at test distance (10 cm) which is between the edge of the charger and the geometric center of probe.
- The highest emission level was recorded and compared with limit as soon as measurement of each points (A, B, C, D, E, F) were completed.
- The EUT were measured according to the dictates of KDB 680106 D01v02.

The results shown in this test report refer only to the sample(s) tested unless otherwise stated. This test report cannot be reproduced, except in full, without prior written permission of the Company.

2.3. Equipment Approval Considerations item 5.2 of KDB 680106 D01v02.**a) Power transfer frequency is less than 1 MHz.**

- The device operates in the frequency range from 120 kHz to 190 kHz.

b) Output power from each primary coil is less than 5 watts.

- DC 5 V (Travel adapter output) → Output power from each primary coil : 5 W (Max.)

c) The transfer system includes only single primary and secondary coils. This includes charging systems that may have multiple primary coils and clients that are able to detect and allow coupling only between individual pairs of coils.

- The transfer system includes only single primary and secondary coils. Refer to a photo in the Internal photos.

d) Client device is inserted in or placed directly in contact with the transmitter.

- Client device is placed directly in contact with the transmitter.

e) The maximum coupling surface area of the transmit (charging) device:

- The EUT coupling surface area : $7.2 \text{ cm(W)} \times 7.4 \text{ cm(H)} = 53.28 \text{ cm}^2$,
 $53.28 \text{ cm}^2 < 60 \text{ cm}^2$

f) Aggregate leakage fields at 10 cm surrounding the device from all simultaneous transmitting coils are demonstrated to be less than 30 % of the MPE limit.

- Refer to following test results.

The EUT field strength levels < 30 % of the MPE limit 1.63 A/m

0.236 A/m (Max.) < 0.489 A/m

The results shown in this test report refer only to the sample(s) tested unless otherwise stated. This test report cannot be reproduced, except in full, without prior written permission of the Company.

2.4. Environmental evaluation and exposure limit according to FCC CFR 47 part 1, 1.1307(b), 1.1310

§1.1310 : The criteria listed in the following table shall be used to evaluate the environment impact of human exposure to radio frequency (RF) radiation as specified in §1.1307(b), except in the case of portable devices which shall be evaluated according to the provisions of FCC part 2.1093 of this chapter

TABLE 1 - LIMITS FOR MAXIMUM PERMISSIBLE EXPOSURE (MPE)

Frequency Range (MHz)	Electric Field Strength(V/m)	Magnetic Field Strength (A/m)	Power Density (mW/cm ²)	Average Time (minutes)
(A) Limits for Occupational /Control Exposures				
0.3 – 3.0	614	1.63	*(100)	6
3.0 – 30	1842/f	4.89/f	*(900/f ²)	6
30 – 300	61.4	0.163	1.0	6
300 – 1 500			f/300	6
1 500 – 100 000			5	6
(B) Limits for General Population / Uncontrol Exposures				
<u>0.3 – 1.34</u>	<u>614</u>	<u>1.63</u>	*(100)	30
1.34 – 30	824/f	2.19/f	*(180/f ²)	30
30 – 300	27.5	0.073	0.2	30
300 – 1 500			f/1 500	30
1 500 – 100 000			1.0	30

f = frequency in MHz

* = Plane wave equivalent power density

Note 1 to Table 1: Occupational/controlled limits apply in situations in which persons are exposed as a consequence of their employment provided those persons are fully aware of the potential for exposure and can exercise control over their exposure. Limits for occupational/controlled exposure also apply in situations when an individual is transient through a location where occupational/controlled limits apply provided he or she is made aware of the potential for exposure.

Note 2 to Table 1: General population/uncontrolled exposures apply in situations in which the general public may be exposed, or in which persons that are exposed as a consequence of their employment may not be fully aware of the potential for exposure or can not exercise control over their exposure.

The results shown in this test report refer only to the sample(s) tested unless otherwise stated. This test report cannot be reproduced, except in full, without prior written permission of the Company.

2.5. E and H field strength

Ambient temperature : (23 ± 1) °C
Relative humidity : 47 % R.H.

2.5.1. E-Field Strength at 10 cm from the edges surrounding the EUT

Test Mode : Normal charging mode with client device

Test condition: Charging mode (less than 1 % battery status of client device)

Frequency Range (kHz)	Probe Position A (V/m)	Probe Position B (V/m)	Probe Position C (V/m)	Probe Position D (V/m)	Probe Position E (V/m)	Probe Position F (V/m)	Limits (V/m)
120 ~ 190	3.433	4.185	3.645	4.474	3.048	2.003	614.00

Test condition: Charging mode (less than 50 % battery status of client device)

Frequency Range (kHz)	Probe Position A (V/m)	Probe Position B (V/m)	Probe Position C (V/m)	Probe Position D (V/m)	Probe Position E (V/m)	Probe Position F (V/m)	Limits (V/m)
120 ~ 190	5.234	5.735	4.672	4.481	2.202	2.373	614.00

Test condition: Charging mode (100 % battery status of client device)

Frequency Range (kHz)	Probe Position A (V/m)	Probe Position B (V/m)	Probe Position C (V/m)	Probe Position D (V/m)	Probe Position E (V/m)	Probe Position F (V/m)	Limits (V/m)
120 ~ 190	8.036	3.627	7.796	7.648	2.654	2.307	614.00

The results shown in this test report refer only to the sample(s) tested unless otherwise stated. This test report cannot be reproduced, except in full, without prior written permission of the Company.

2.5.2. H-Field Strength at 10 cm from the edges surrounding the EUT

Test Mode : Normal charging mode with client device

Test condition: Charging mode (less than 1 % battery status of client device)

Frequency Range (kHz)	Probe Position A (A/m)	Probe Position B (A/m)	Probe Position C (A/m)	Probe Position D (A/m)	Probe Position E (A/m)	Probe Position F (A/m)	Limits (A/m)
120 ~ 190	0.052	0.057	0.041	0.090	0.050	0.236	1.63

Test condition: Charging mode (less than 50 % battery status of client device)

Frequency Range (kHz)	Probe Position A (A/m)	Probe Position B (A/m)	Probe Position C (A/m)	Probe Position D (A/m)	Probe Position E (A/m)	Probe Position F (A/m)	Limits (A/m)
120 ~ 190	0.038	0.050	0.077	0.110	0.137	0.182	1.63

Test condition: Charging mode (100 % battery status of client device)

Frequency Range (kHz)	Probe Position A (A/m)	Probe Position B (A/m)	Probe Position C (A/m)	Probe Position D (A/m)	Probe Position E (A/m)	Probe Position F (A/m)	Limits (A/m)
120 ~ 190	0.104	0.141	0.133	0.082	0.070	0.115	1.63

The results shown in this test report refer only to the sample(s) tested unless otherwise stated. This test report cannot be reproduced, except in full, without prior written permission of the Company.